

# Deep Learning Loss Function and Data Optimization for A.I. Detection of Thin Film Grain Boundaries

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## Background

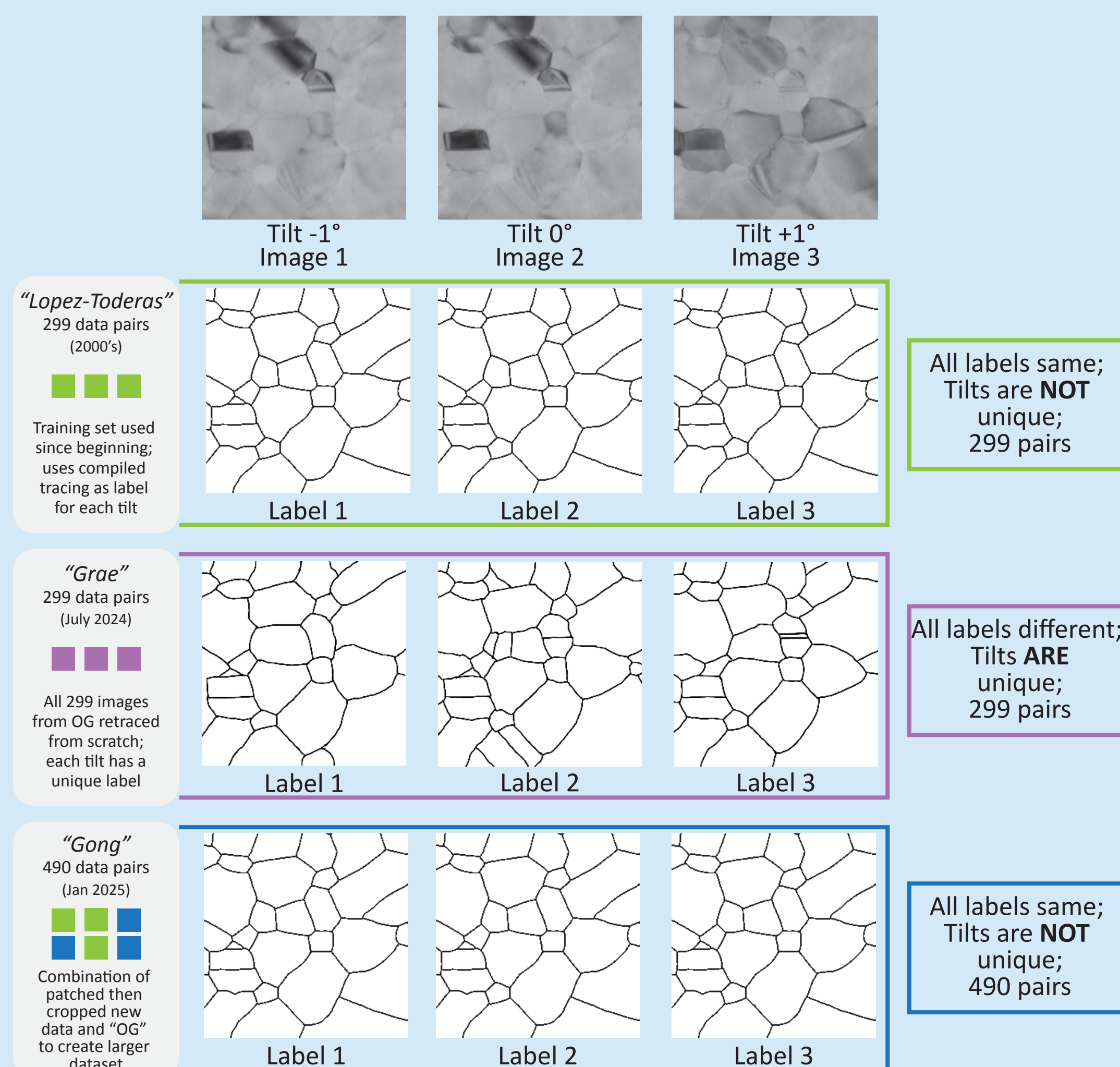
- Understanding microstructural features of materials is essential for predicting materials' properties.
- Grain boundaries significantly influence mechanical strength, ductility, electrical resistivity, corrosion resistance, and thermal properties of metals and alloys.
- Tracing grain boundaries is crucial for determining the sizes of grains, but it is a labor-intensive, subjective task.
- A U-Net architecture [1], widely used in image segmentation, has shown promise for automated grain boundary tracing [2].
- Various loss functions can be employed to train and validate such a model, each potentially emphasizing different aspects of learning (e.g., boundary accuracy vs. robustness to data variability) [3].

## Purpose

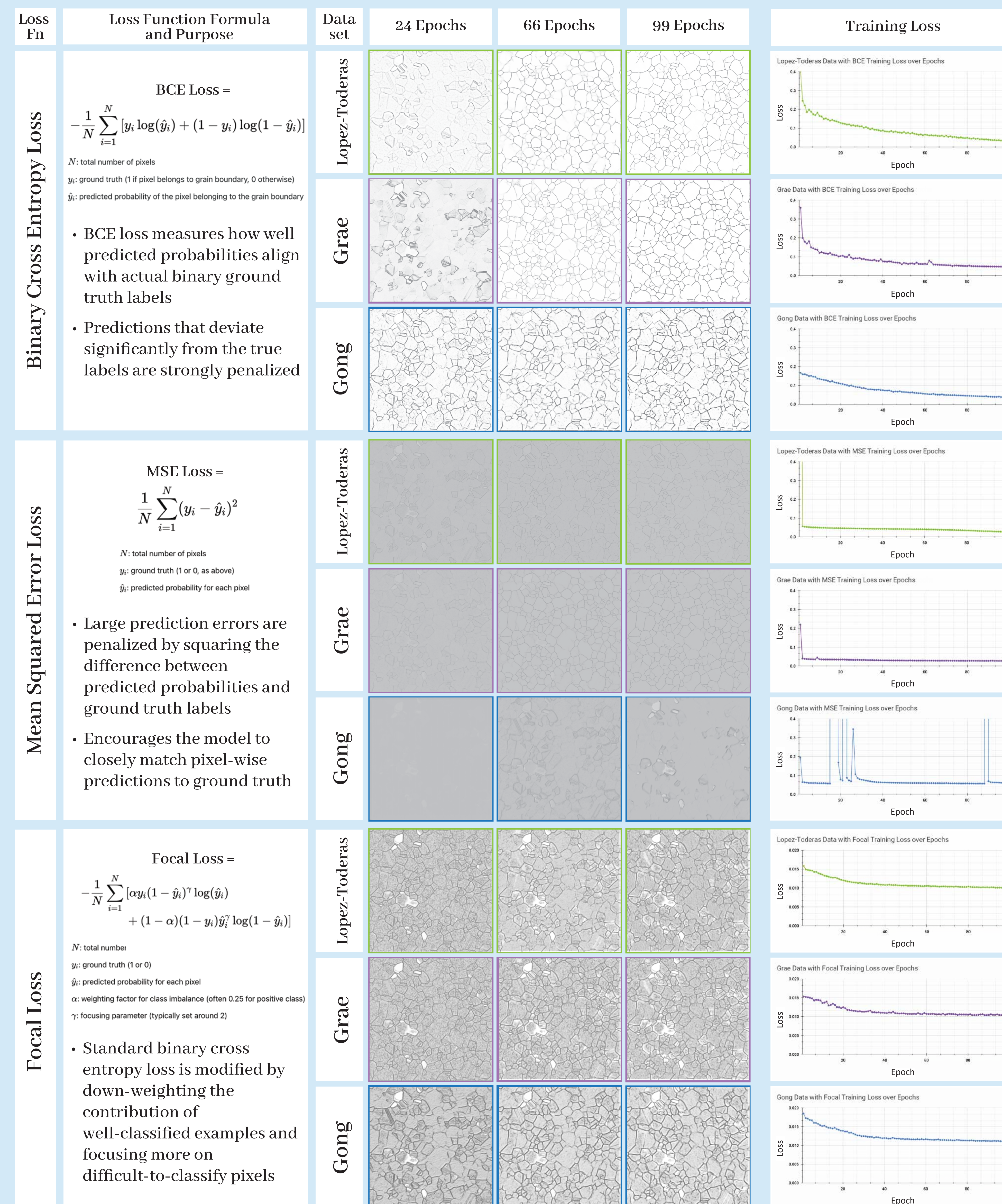
- Identify optimal combination of loss function and data to create a model that can generates an automated tracing most consistent with the ground truth
- Explore if quality or quantity is more important for dataset construction when training a U-Net model.

## Methods

- Trained for 99 epochs using one of three built-in PyTorch loss functions, one of three prepared dataset (see below), ran inference test on on test image not in training set



## Results



## Conclusions

### Loss Functions Analysis

- Can qualitatively determine that BCE performs better than the other two loss functions given its closest visual resemblance to a tracing needed for post processing overlay applications

### Datasets Analysis

- As expected, the Gong dataset experienced less loss with the model learning quicker from a larger dataset
- The Gong inference outputs appear to trace noise within the grains rather than their boundaries. This becomes most pronounced at 99 epochs indicating potential overfitting at earlier point in training than other two datasets
- Within the BCE results, the Grae dataset experienced more loss and has a larger minma than the Lopez-Toderas dataset; however, the Grae dataset is less prone to overfitting than the Lopez-Toderas dataset as per the train validation loss results
- Additionally, the Grae dataset is qualitatively superior
- At both 66 and 99 epochs Grae surpasses Lopez-Toderas in identifying smaller grains; Lopez-Toderas appears to output inferences with greater confidence at expense of complete tracing
- This indicates that a lesser quantity of higher quality data—for a U-Net architecture— out performs an equal or larger quantity of lower quality data in machine learning

### Future Work

- Quantitative comparison of the methods using grain size distributions
- Experiment with more loss functions especially those not built into PyTorch
- Investigate if the construction of a fourth dataset with the same number of datum as Gong but created through the same approach as the Grae dataset will significantly improve model performance (quality and quantity)

## References

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- [3] Patrick, M., Eckstein, J., Lopez, J., Toderas, S., Asher, S., Whang, S., Levine, S., Rickman, J., Barmak, K. (2023). Automated Grain Boundary Detection for Bright-Field Transmission Electron Microscopy Images via U-Net. Microscopy and Microanalysis. 29. 10.1093/micmic/ozad115.

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